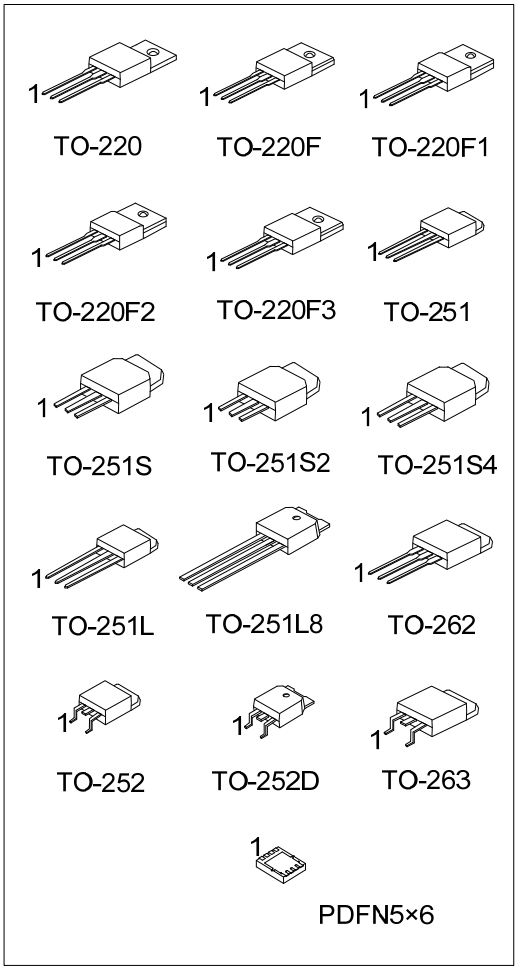
4N65-Q

Power MOSFET

4.0A, 650V N-CHANNEL POWER MOSFET



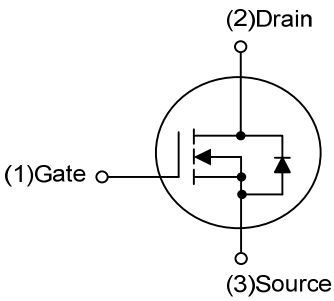
■ DESCRIPTION

The UTC **4N65-Q** is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristic. This power MOSFET is usually used in high speed switching applications including power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

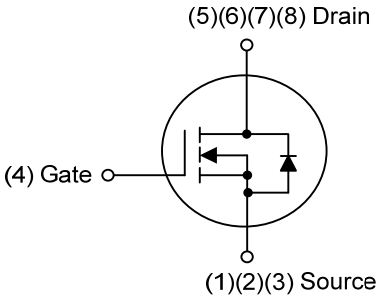
■ FEATURES

* $R_{DS(ON)} \leq 3.1\ \Omega$ @ V_{GS}=10V, I_D=2.2A
* Fast Switching Capability
* Avalanche Energy Specified
* Improved dv/dt Capability, High Ruggedness

■ SYMBOL



TO-220/TO-220F/TO-220F1
TO-220F2/TO-220F3/TO-251
TO-251S/TO-251L/TO-251L8
TO-251S2/TO-251S4/TO-252
TO-252D/TO-262/TO-263

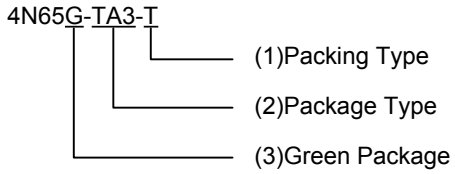


PDFN5×6

■ ORDERING INFORMATION

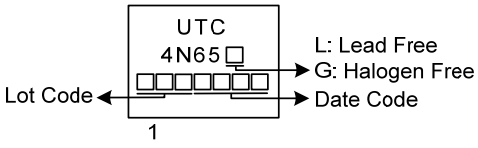
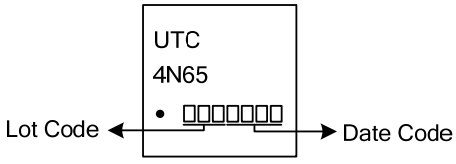
Ordering Number		Package	Pin Assignment								Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	
4N65L-TA3-T	4N65G-TA3-T	TO-220	G	D	S	-	-	-	-	-	Tube
4N65L-TF1-T	4N65G-TF1-T	TO-220F1	G	D	S	-	-	-	-	-	Tube
4N65L-TF2-T	4N65G-TF2-T	TO-220F2	G	D	S	-	-	-	-	-	Tube
4N65L-TF3T-T	4N65G-TF3T-T	TO-220F3	G	D	S	-	-	-	-	-	Tube
4N65L-TF3-T	4N65G-TF3-T	TO-220F	G	D	S	-	-	-	-	-	Tube
4N65L-TM3-T	4N65G-TM3-T	TO-251	G	D	S	-	-	-	-	-	Tube
4N65L-TMA-T	4N65G-TMA-T	TO-251L	G	D	S	-	-	-	-	-	Tube
4N65L-TMA8-T	4N65G-TMA8-T	TO-251L8	G	D	S	-	-	-	-	-	Tube
4N65L-TMS-T	4N65G-TMS-T	TO-251S	G	D	S	-	-	-	-	-	Tube
4N65L-TMS2-T	4N65G-TMS2-T	TO-251S2	G	D	S	-	-	-	-	-	Tube
4N65L-TMS4-T	4N65G-TMS4-T	TO-251S4	G	D	S	-	-	-	-	-	Tube
4N65L-TN3-R	4N65G-TN3-R	TO-252	G	D	S	-	-	-	-	-	Tape Reel
4N65L-TND-R	4N65G-TND-R	TO-252D	G	D	S	-	-	-	-	-	Tape Reel
4N65L-T2Q-T	4N65G-T2Q-T	TO-262	G	D	S	-	-	-	-	-	Tube
4N65L-TQ2-R	4N65G-TQ2-R	TO-263	G	D	S	-	-	-	-	-	Tape Reel
4N65L-TQ2-T	4N65G-TQ2-T	TO-263	G	D	S	-	-	-	-	-	Tube
4N65L-P5060-R	4N65G-P5060-R	PDFN5×6	S	S	S	G	D	D	D	D	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



(1) T: Tube, R: Tape Reel
(2) TA3: TO-220, TF1: TO-220F1, TF2: TO-220F2
TF3: TO-220F, TF3T: TO-220F3, TM3: TO-251,
TMA: TO-251L, TMA8: TO-251L8, TMS: TO-251S,
TMS2: TO-251S2, TN3: TO-252, TMS4: TO-251S4,
TND: TO-252D, T2Q: TO-262, TQ2: TO-263,
P5060: PDFN5×6
(3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING

PACKAGE		MARKING
TO-220 TO-220F TO-220F1 TO-220F2 TO-220F3 TO-251 TO-251L TO-251L8	TO-251S TO-251S2 TO-251S4 TO-252 TO-252D TO-262 TO-263	
PDFN5×6		

■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	±30	V
Avalanche Current (Note2)		I_{AR}	4.4	A
Drain Current	Continuous	I_D	4.0	A
	Pulsed (Note2)	I_{DM}	16	A
Avalanche Energy	Single Pulsed (Note3)	E_{AS}	60	mJ
	Repetitive (Note2)	E_{AR}	10.6	mJ
Peak Diode Recovery dv/dt (Note4)		dv/dt	4.5	V/ns
Power Dissipation	TO-220/TO-262/TO-263	P_D	106	W
	TO-220F/TO-220F1 TO-220F3		36	W
	TO-220F2		38	W
	TO-251/TO-251L TO-251L8/TO-251S TO-251S2/TO-251S4 TO-252/TO-252D		50	W
	PDFN5×6		30	W
Junction Temperature		T_J	+150	°C
Operating Temperature		T_{OPR}	-55 ~ +150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L = 30mH, I_{AS} = 2.1A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C
4. I_{SD}≤4.4A, di/dt ≤200A/μs, V_{DD}≤BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

PARAMETER	PACKAGE	SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220/TO-262/TO-263 TO-220F/TO-220F1 TO-220F2/TO-220F3	θ_{JA}	62.5	°C/W
	TO-251/TO-251L TO-251L8/TO-251S TO-251S2/TO-251S4 TO-252/TO-252D		83	°C/W
	PDFN5×6		75 (Note)	°C/W
Junction to Case	TO-220/TO-262/TO-263	θ_{JC}	1.18	°C/W
	TO-220F/TO-220F1 TP-220F3		3.47	°C/W
	TO-220F2		3.28	°C/W
	TO-251/TO-251L TO-251L8/TO-251S TO-251S2/TO-251S4 TO-252/TO-252D		2.5	°C/W
	PDFN5×6		4.17 (Note)	°C/W

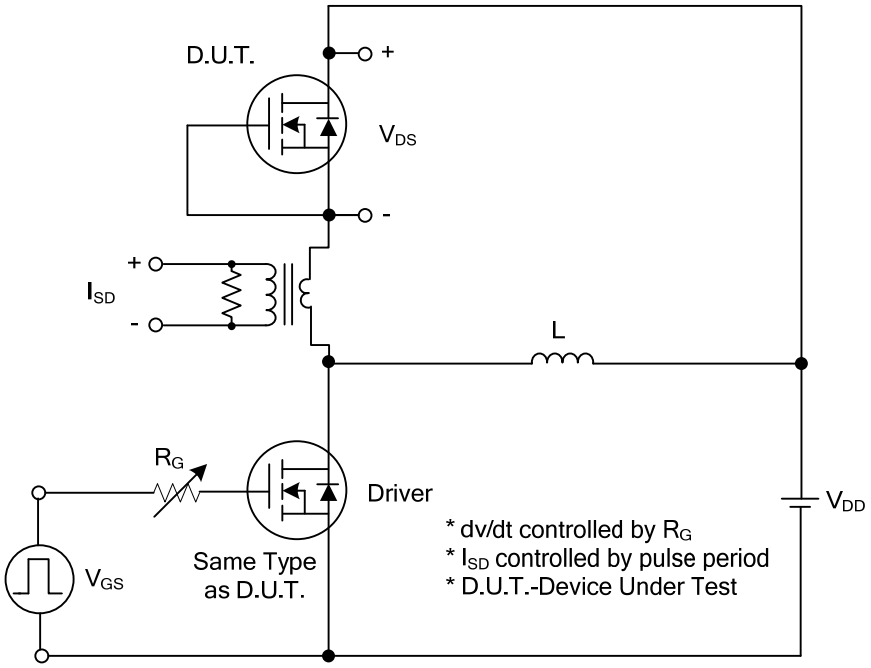
Note: The data tested by surface mounted on a 1 $inch^2$ FR-4 board with 2OZ copper.

■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

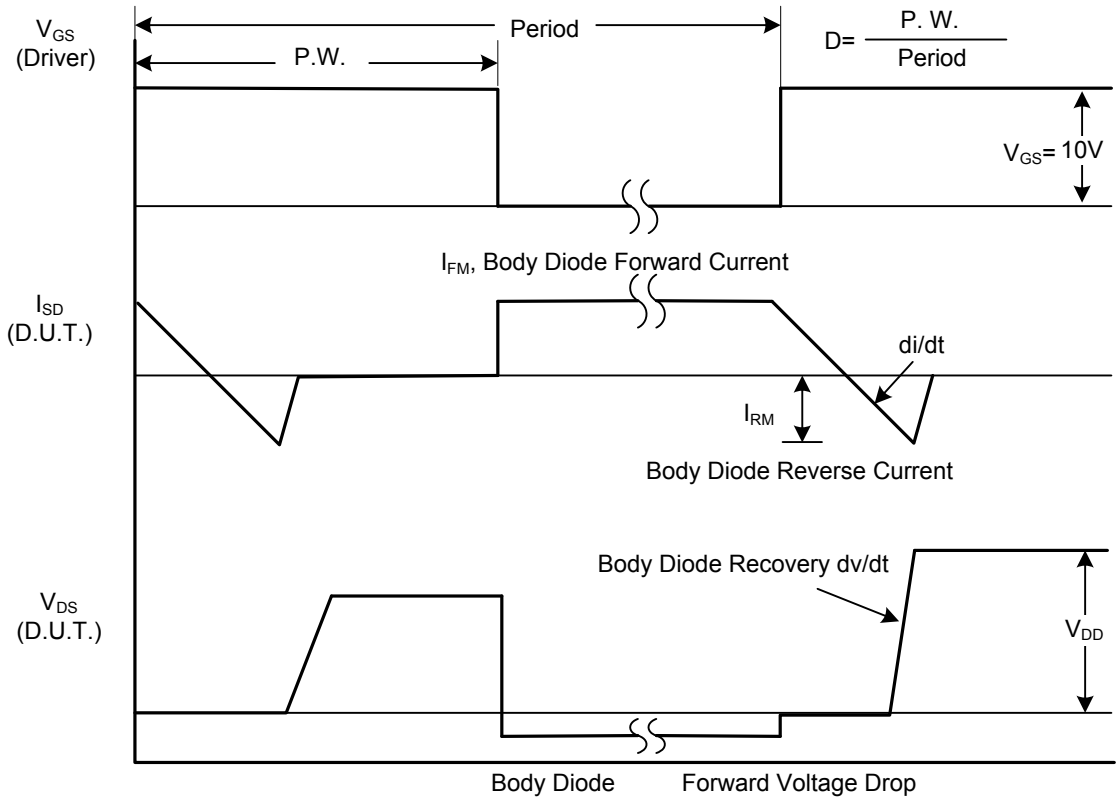
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V_{GS} = 0 V, I_D = 250μA	650			V
Drain-Source Leakage Current		I_{DSS}	V_{DS} = 650 V, V_{GS} = 0 V			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS} = 30 V, V_{DS} = 0 V			100	nA
	Reverse		V_{GS} = -30 V, V_{DS} = 0 V			-100	nA
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_J$	I_D=250μA, Referenced to 25°C		0.6		V/°C
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS} = V_{GS}, I_D = 250μA	2.0		4.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS} = 10 V, I_D = 2.2A		2.9	3.1	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}	V_{GS}=V, V_{DS}=25V, f=1MHz		470	530	pF
Output Capacitance		C_{OSS}			50	70	pF
Reverse Transfer Capacitance		C_{RSS}			10	13	pF
SWITCHING CHARACTERISTICS							
Total Gate Charge (Note 1)		Q_G	V_{DS}=520V, I_D= 4.0A, V_{GS}=10V (Note 1, 2)		55	75	nC
Gate-Source Charge		Q_{GS}			15	21	nC
Gate-Drain Charge		Q_{GD}			18	24	nC
Turn-On Delay Time (Note 1)		$t_{D(ON)}$	V_{DS}=325V, I_D 4.0A, R_G=25Ω (Note 1, 2)		38	75	ns
Turn-On Rise Time		t_R			45	85	ns
Turn-Off Delay Time		$t_{D(OFF)}$			90	130	ns
Turn-Off Fall Time		t_F			35	80	ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Continuous Drain-Source Diode Forward Current		I_S				4.4	A
Maximum Pulsed Drain-Source Diode Forward Current		I_{SM}				17.6	A
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	V_{GS} = 0 V, I_S = 4.4A			1.4	V
Reverse Recovery Time (Note 1)		t_{rr}	V_{GS} = 0V, I_S = 4.4A, dI_F/dt = 100 A/μs (Note 1)		250		ns
Reverse Recovery Charge		Q_{rr}			1.5		μC

Note: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

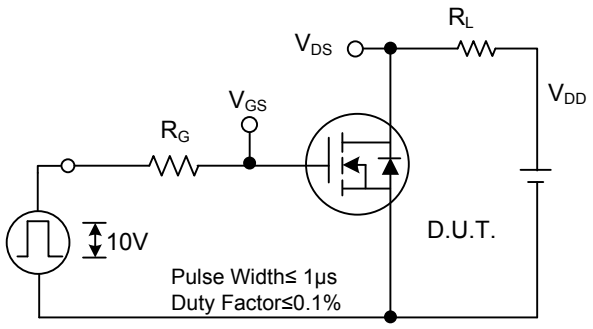


Peak Diode Recovery dv/dt Test Circuit

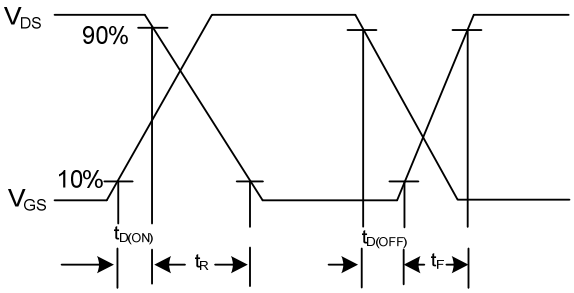


Peak Diode Recovery dv/dt Waveforms

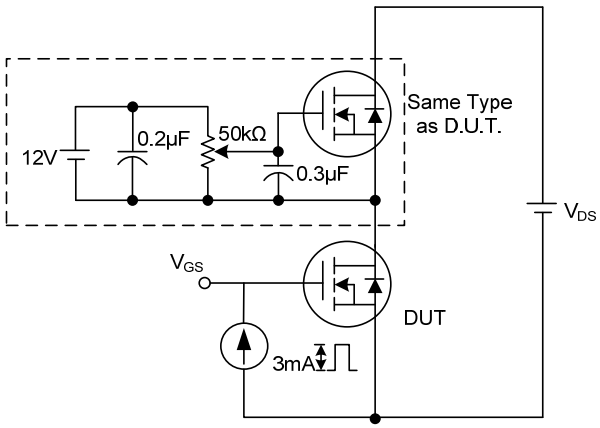
■ TEST CIRCUITS AND WAVEFORMS



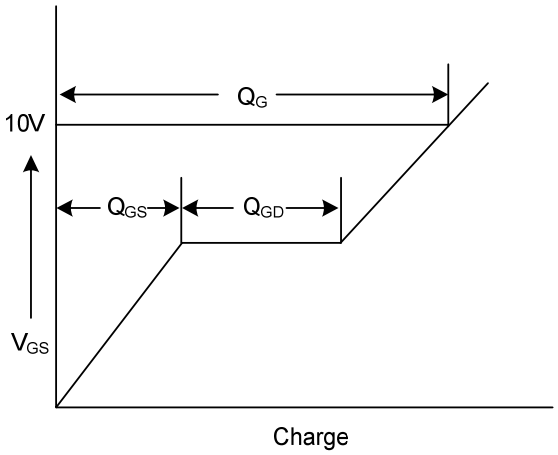
Switching Test Circuit



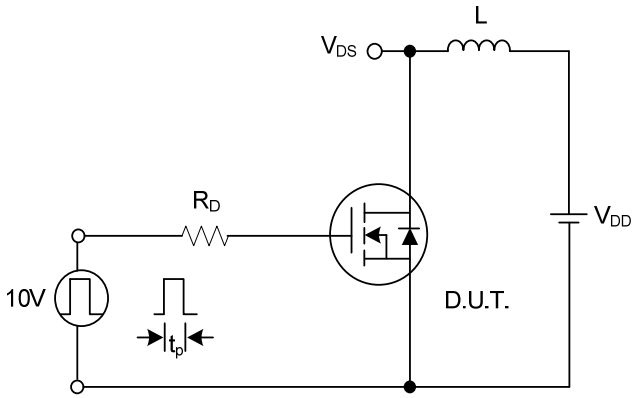
Switching Waveforms



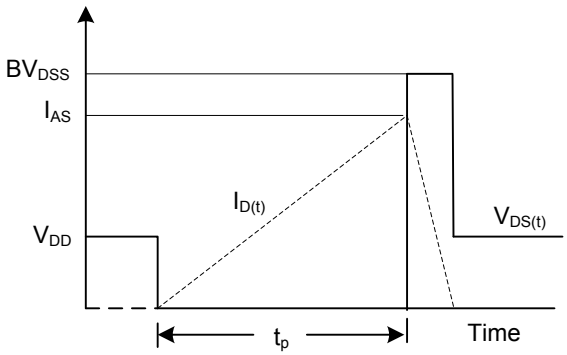
Gate Charge Test Circuit



Gate Charge Waveform



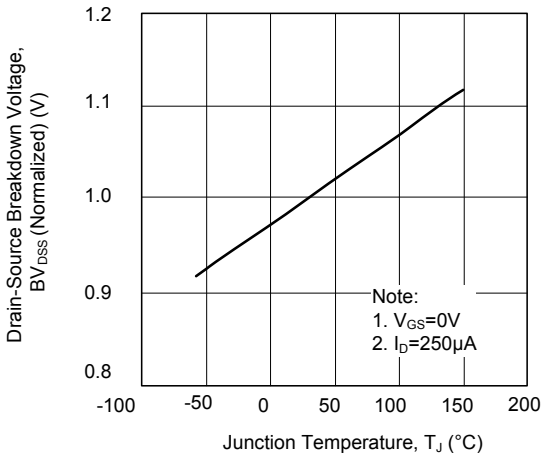
Unclamped Inductive Switching Test Circuit



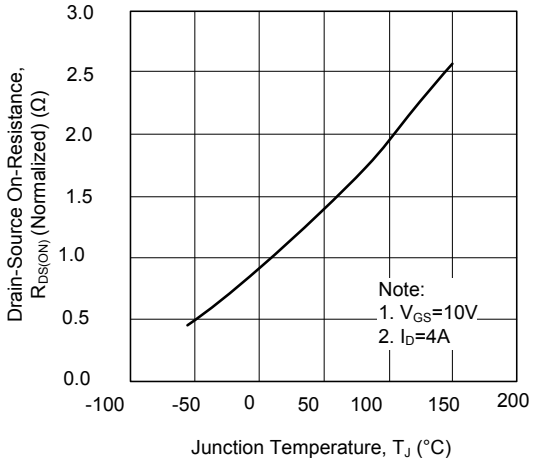
Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS

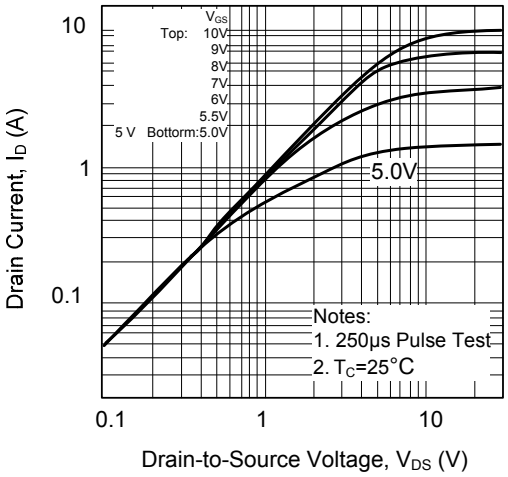
Breakdown Voltage Variation vs. Temperature



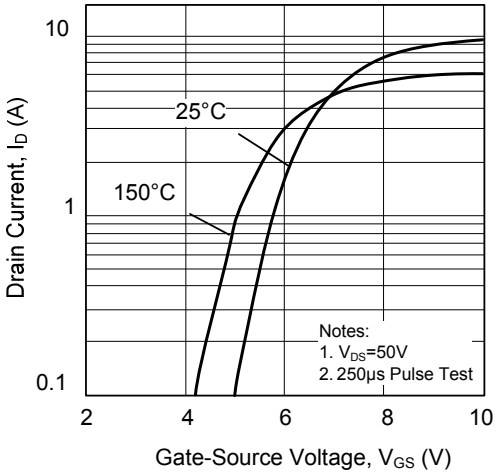
On-Resistance Junction Temperature



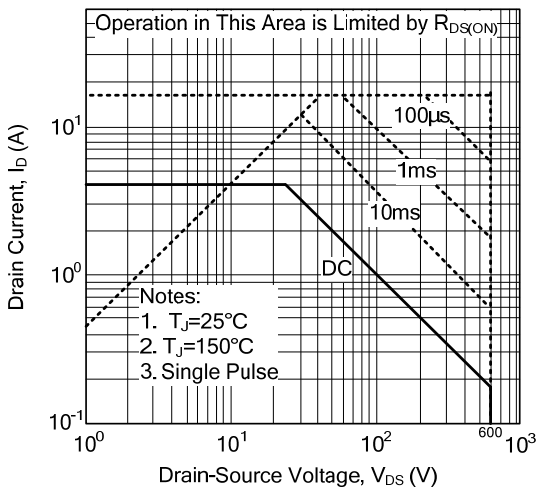
On-State Characteristics



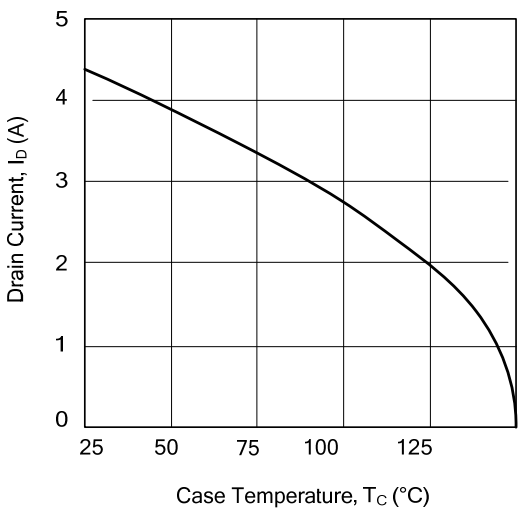
Transfer Characteristics



Safe Operating Area

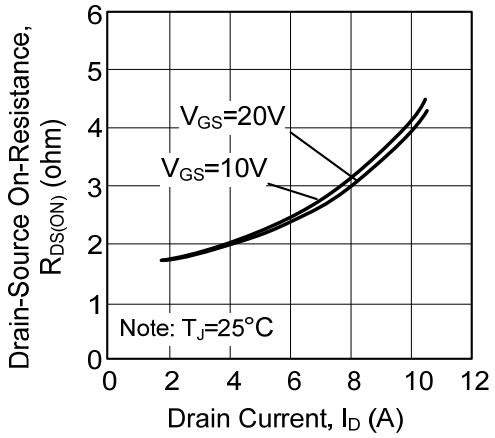


Maximum Drain Current vs. Case Temperature

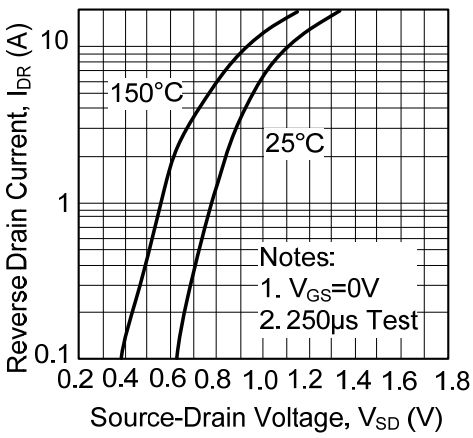


■ TYPICAL CHARACTERISTICS (Cont.)

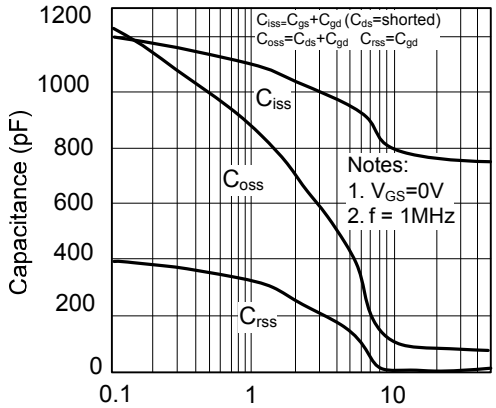
On-Resistance Variation vs. Drain Current and Gate Voltage



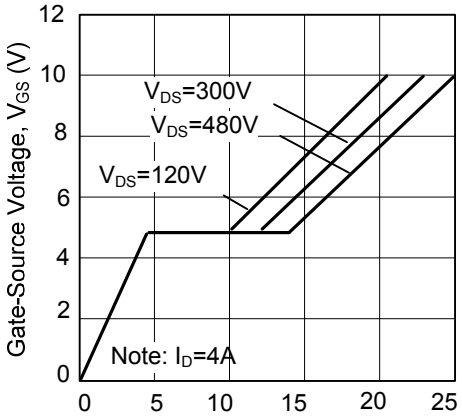
On State Current vs. Allowable Case Temperature



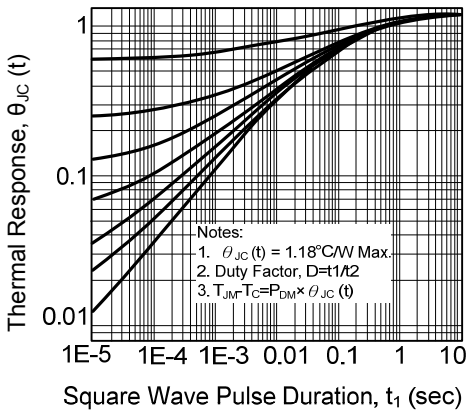
Capacitance Characteristics (Non-Repetitive)



Gate Charge Characteristics



Transient Thermal Response Curve



Power Dissipation